

1-Mbit (64 K × 16) Static RAM

Features

- Temperature Ranges:

 ☐ Industrial: -40 °C to 85 °C

 ☐ Automotive-A: -40 °C to 85 °C
- Pin and Function Compatible with CY7C1021B
- High Speed
 □ t_{AA} = 10 ns
- Low Active Power
 □ I_{CC} = 80 mA at 10 ns
- Low CMOS Standby Power
 □ I_{SB2} = 3 mA
- 2.0 V Data Retention
- Automatic Power Down when Deselected
- CMOS for Optimum Speed and Power
- Independent Control of Upper and Lower Bits
- Available in Pb-free 44-pin 400-Mil Wide Molded SOJ and 44-pin TSOP II Packages

Functional Description

The CY7C1021D is a high performance CMOS static RAM organized as 65,536 words by 16 bits. This device has an

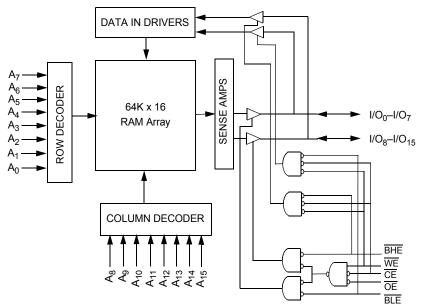
automatic power down feature that significantly reduces power consumption when deselected. The input and output pins (I/O $_0$ through I/O $_{15}$) are placed in a high impedance state when the device is deselected (CE HIGH), outputs are disabled (OE HIGH), BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation (CE LOW and WE LOW).

Write to the device by taking Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW. If Byte Low Enable (\overline{BLE}) is LOW, then data from I/O pins $(I/O_0$ through $I/O_7)$, is written into the location specified on the address pins $(A_0$ through A_{15}). If Byte High Enable (\overline{BHE}) is LOW, then data from I/O pins $(I/O_8$ through I/O_{15}) is written into the location specified on the address pins $(A_0$ through $A_{15})$.

Read from the device by taking Chip Enable $(\overline{\text{CE}})$ and Output Enable $(\overline{\text{OE}})$ LOW while forcing the Write Enable $(\overline{\text{WE}})$ HIGH. If Byte Low Enable $(\overline{\text{BLE}})$ is LOW, then data from the memory location specified by the address pins appears on I/O $_0$ to I/O $_7$. If Byte High Enable (BHE) is LOW, then data from memory appears on I/O $_8$ to I/O $_{15}$. See the Truth Table on page 10 for a complete description of read and write modes.

The CY7C1021D device is suitable for interfacing with processors that have TTL I/P levels. It is not suitable for processors that require CMOS I/P levels. Please see Electrical Characteristics on page 4 for more details and suggested alternatives.

Logic Block Diagram







Contents

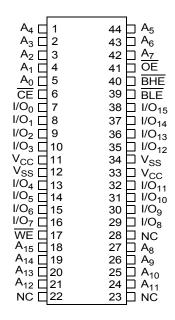
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Pin Configurations

Figure 1. 44-pin SOJ / 44-pin TSOP II pinout (Top View) [1]



Selection Guide

Description	-10 (Industrial / Automotive-A)	Unit
Maximum Access Time	10	ns
Maximum Operating Current	80	mA
Maximum CMOS Standby Current	3	mA

Note

NC pins are not connected on the die.



Maximum Ratings

Exceeding the maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature-65 °C to +150 °C Ambient Temperature with

Supply Voltage on V_{CC} to Relative $\mbox{GND}^{[2]}$ –0.5 V to +6.0 V

DC Voltage Applied to Outputs in High Z State $^{[2]}$ -0.5 V to V $_{\rm CC}$ + 0.5 V

DC Input Voltage [2]	0.5 V to V _{CC} + 0.5 V
Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch Up Current	> 200 mA

Operating Range

Range	Ambient Temperature	V _{CC}	Speed	
Industrial	–40 °C to +85 °C	5 V ± 10%	10 ns	
Automotive-A				

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions			lustrial / otive-A)	Unit
	·		Min	Max		
V _{OH}	Output HIGH Voltage	I _{OH} = -4.0 mA		2.4	_	V
		$I_{OH} = -0.1 \text{ mA}$		_	3.4 ^[3]	
V _{OL}	Output LOW Voltage	I _{OL} = 8.0 mA		_	0.4	V
V _{IH}	Input HIGH Voltage			2.2	V _{CC} + 0.5 V	V
V _{IL}	Input LOW Voltage [2]					V
I _{IX}	Input Leakage Current	$GND \leq V_I \leq V_CC$	$GND \le V_{I} \le V_{CC}$			μА
I _{OZ}	Output Leakage Current	$GND \le V_I \le V_{CC}$, Output Disabled	$GND \le V_I \le V_{CC}$, Output Disabled			μА
I _{CC}	V _{CC} Operating Supply Current	V _{CC} = Max, I _{OUT} = 0 mA,	100 MHz	_	80	mA
	$T = T_{\text{max}} = 1/T_{\text{RC}}$	$f = f_{max} = 1/t_{RC}$	83 MHz	_	72	mA
			66 MHz	_	58	mA
			40 MHz	_	37	mA
I _{SB1}	Automatic CE Power Down Current –TTL Inputs	Max V_{CC} , $\overline{CE} \ge V_{IH}$, $V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IH}$	-	10	mA	
I _{SB2}	Automatic CE Power Down Current – CMOS Inputs	$\begin{aligned} &\text{Max V}_{CC}, \overline{CE} \geq \text{V}_{CC} - 0.3 \text{ V}, \text{V}_{IN} \geq \text{V}_{C} \\ &\text{V}_{IN} \leq 0.3 \text{ V}, \text{f} = 0 \end{aligned}$	_C – 0.3 V, or	-	3	mA

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V_{IL} (min) = -2.0 V and V_{IH}(max) = V_{CC} + 1 V for pulse durations of less than 5 ns.
 Please note that the maximum V_{OH} limit does not exceed minimum CMOS V_{IH} of 3.5 V. If you are interfacing this SRAM with 5 V legacy processors that require a minimum V_{IH} of 3.5 V, please refer to Application Note AN6081 for technical details and options you may consider.



Capacitance

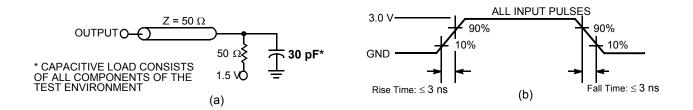
Parameter [4]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 5.0 \text{V}$	8	pF
C _{OUT}	Output capacitance		8	pF

Thermal Resistance

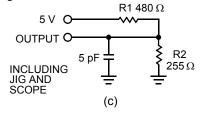
Parameter [4]	Description	Test Conditions	44-pin SOJ	44-pin TSOP II	Unit
Θ_{JA}		Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	59.52	53.91	°C/W
Θ^{JC}	Thermal resistance (junction to case)		36.75	21.24	°C/W

AC Test Loads and Waveforms

Figure 2. AC Test Loads and Waveforms [5]



High-Z characteristics:



Notes

- 4. Tested initially and after any design or process changes that may affect these parameters.
 5. AC characteristics (except High Z) are tested using the load conditions shown in Figure 2 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 2 (c).

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Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions	Min	Max	Unit
V_{DR}	V _{CC} for Data Retention		2.0	-	V
I _{CCDR}	Data Retention Current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V}$	_	3	mA
t _{CDR} ^[6]	Chip Deselect to Data Retention Time		0	-	ns
t _R ^[7]	Operation Recovery Time		t _{RC}	-	ns

Data Retention Waveform

Figure 3. Data Retention Waveform



Notes

 ^{6.} V_{IL} (min) = -2.0 V and V_{IH}(max) = V_{CC} + 1 V for pulse durations of less than 5 ns.
 7. Full device operation requires linear V_{CC} ramp from V_{DR} to V_{CC(min)} ≥ 50 μs or stable at V_{CC(min)} ≥ 50 μs.



Switching Characteristics

Over the Operating Range

Parameter [8]	Description	-10 (Ind Autom	ustrial / otive-A)	Unit
		Min	Max]
Read Cycle		<u> </u>		
t _{power} [9]	V _{CC} (typical) to the first access	100	_	μS
t _{RC}	Read Cycle Time	10	_	ns
t _{AA}	Address to Data Valid	_	10	ns
t _{OHA}	Data Hold from Address Change	3	_	ns
t _{ACE}	CE LOW to Data Valid	_	10	ns
t _{DOE}	OE LOW to Data Valid	_	5	ns
t _{LZOE}	OE LOW to Low Z [10]	0	_	ns
t _{HZOE}	OE HIGH to High Z [10, 11]	_	5	ns
t _{LZCE}	CE LOW to Low Z [10]	3	_	ns
t _{HZCE}	CE HIGH to High Z [10, 11]	_	5	ns
t _{PU}	CE LOW to Power-Up	0	_	ns
t _{PD}	CE HIGH to Power-Down	_	10	ns
t _{DBE}	Byte Enable to Data Valid	_	5	ns
t _{LZBE}	Byte Enable to Low Z	0	_	ns
t _{HZBE}	Byte Disable to High Z	_	5	ns
Write Cycle [1	2]	·		
t _{WC}	Write Cycle Time	10	_	ns
t _{SCE}	CE LOW to Write End	7	_	ns
t _{AW}	Address Setup to Write End	7	_	ns
t _{HA}	Address Hold from Write End	0	_	ns
t _{SA}	Address Setup to Write Start	0	_	ns
t _{PWE}	WE Pulse Width	7	_	ns
t _{SD}	Data Setup to Write End	6	_	ns
t _{HD}	Data Hold from Write End	0	_	ns
t _{LZWE}	WE HIGH to Low Z [10]	3	_	ns
t _{HZWE}	WE LOW to High Z [10, 11]	_	5	ns
t _{BW}	Byte Enable to End of Write	7	_	ns

Notes

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^{8.} Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.

^{9.} t_{POWER} gives the minimum amount of time that the power supply should be at typical V_{CC} values until the first memory access can be performed.

10. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} is less than t_{LZWE} for any given device.

11. t_{HZOE}, t_{HZBE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in (c) of Figure 2 on page 5. Transition is measured when the outputs enter a high impedance state.

^{12.} The internal write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE/BLE LOW. CE, WE and BHE/BLE must be LOW to initiate a write, and a LOW to HIGH transition on any of these signals can terminate the write. The input data setup and hold timing should be referenced to the leading edge of the signal that terminates the write.



Switching Waveforms

Figure 4. Read Cycle No. 1 (Address Transition Controlled) [13, 14]

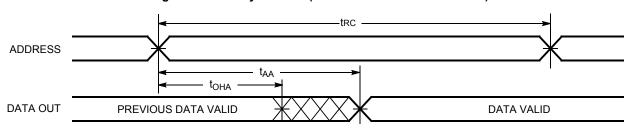
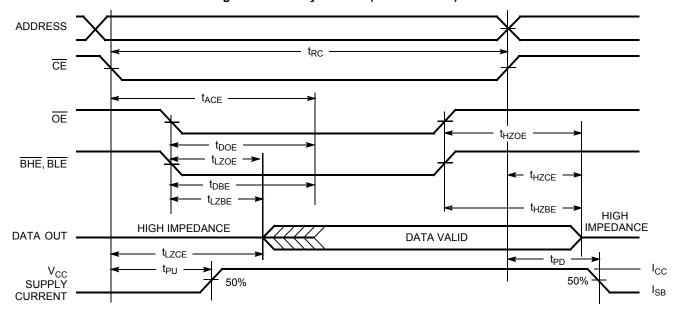


Figure 5. Read Cycle No. 2 (OE Controlled) [14, 15]



Notes

^{13.} Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} and/or $\overline{BLE} = V_{\parallel}$.

^{14.} WE is HIGH for read cycle.

^{15.} Address valid prior to or coincident with $\overline{\text{CE}}$ transition LOW.



Switching Waveforms (continued)

Figure 6. Write Cycle No. 1 (CE Controlled) [16, 17]

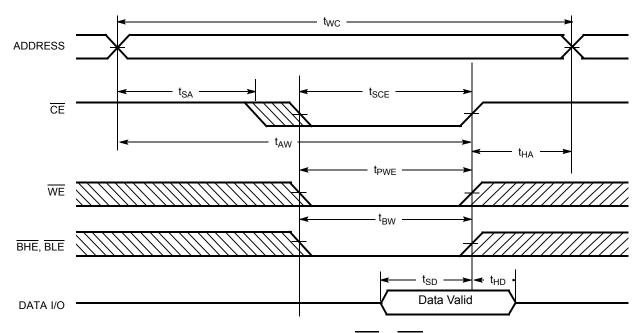
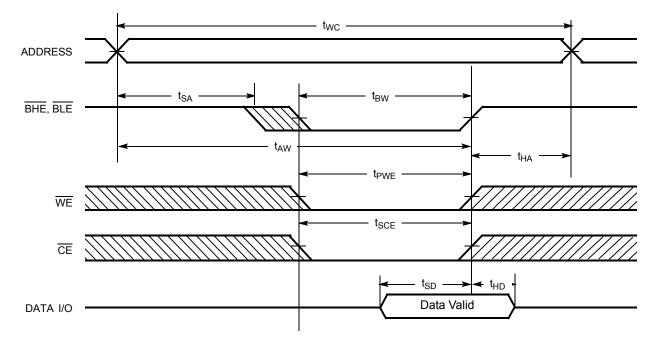


Figure 7. Write Cycle No. 2 (BLE or BHE Controlled)



Notes

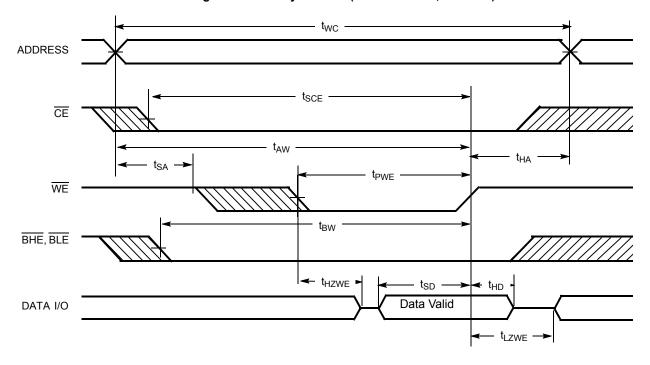
^{16.} Data I/O is high impedance if OE or BHE and/or BLE = V_{IH}.

17. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



Switching Waveforms (continued)

Figure 8. Write Cycle No. 3 (WE Controlled, OE LOW)



Truth Table

CE	OE	WE	BLE	BHE	I/O ₀ –I/O ₇	I/O ₈ -I/O ₁₅	Mode	Power
Н	Χ	X	X	Х	High Z	High Z	Power Down	Standby (I _{SB})
L	L	Н	L	L	Data Out	Data Out	Read – All bits	Active (I _{CC})
			L	Н	Data Out	High Z	Read – Lower bits only	Active (I _{CC})
			Н	L	High Z	Data Out	Read – Upper bits only	Active (I _{CC})
L	Χ	L	L	L	Data In	Data In	Write – All bits	Active (I _{CC})
			L	Н	Data In	High Z	Write – Lower bits only	Active (I _{CC})
			Н	L	High Z	Data In	Write – Upper bits only	Active (I _{CC})
L	Н	Н	Х	Х	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})
L	Х	Х	Н	Н	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})

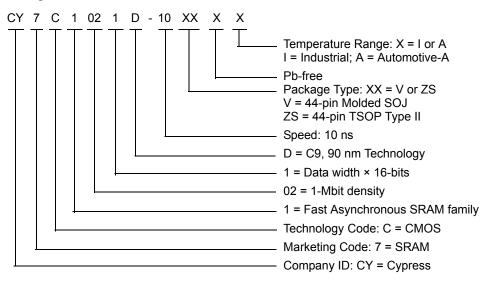


Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1021D-10VXI	51-85082	44-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1021D-10ZSXI	51-85087	44-pin TSOP Type II (Pb-free)	
	CY7C1021D-10ZSXA			Automotive-A

Shaded areas contain advance information. Contact your local Cypress sales representative for availability of these parts.

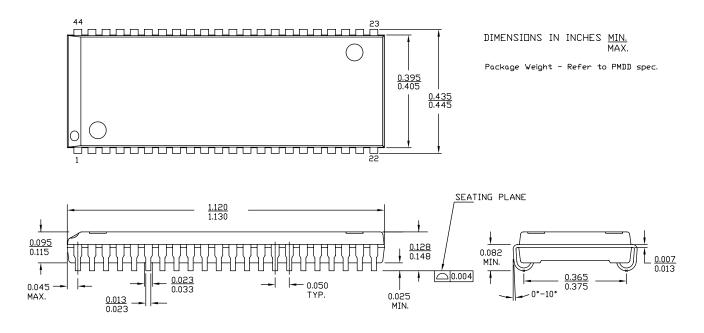
Ordering Code Definitions





Package Diagrams

Figure 9. 44-pin SOJ (400 Mils) V44.4 Package Outline, 51-85082

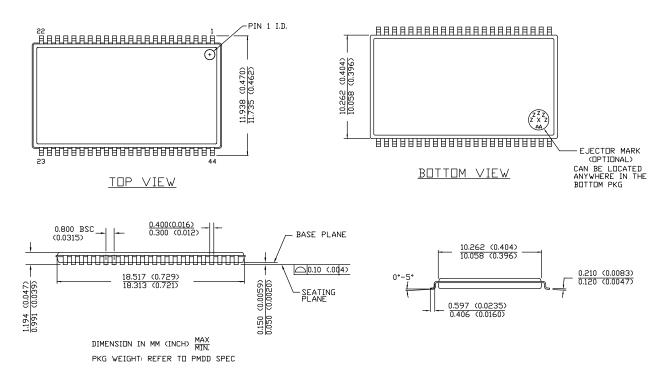


51-85082 *E



Package Diagrams (continued)

Figure 10. 44-pin TSOP Z44-II Package Outline, 51-85087



51-85087 *E



Acronyms

Acronym	Description			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
I/O	Input/Output			
OE	Output Enable			
SOJ	Small Outline J-lead			
SRAM	Static Random Access Memory			
TSOP	Thin Small Outline Package			
TTL	Transistor-Transistor Logic			
WE	Write Enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μΑ	microampere			
μs	microsecond			
mA	milliampere			
mm	millimeter			
ms	millisecond			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

Documen Documen	Document Title: CY7C1021D, 1-Mbit (64 K × 16) Static RAM Document Number: 38-05462						
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change			
**	201560	SWI	See ECN	Advance Information data sheet for C9 IPP			
*A	233695	RKF	See ECN	DC parameters modified as per EROS (Spec # 01-02165) Pb-free Offering in the Ordering Information			
*B	263769	RKF	See ECN	Added Data Retention Characteristics Table Added T _{power} Spec in Switching Characteristics Table Shaded Ordering Information			
*C	307601	RKF	See ECN	Reduced Speed bins to -10 and -12 ns			
*D	520647	VKN	See ECN	Changed status from Preliminary to Final. Removed Commercial Operating range Added I _{CC} values for the frequencies 83MHz, 66MHz and 40MHz Updated Thermal Resistance table Added Automotive Product Information Updated Ordering Information Table Changed Overshoot spec from V _{CC} +2V to V _{CC} +1V in footnote #4			
*E	802877	VKN	See ECN	Changed Commercial operating range $I_{\rm CC}$ spec from 60 mA to 80 mA for 100MHz, 55 mA to 72 mA for 83MHz, 45 mA to 58 mA for 66MHz, 30 mA to 37 mA for 40MHz Changed Automotive operating range $I_{\rm CC}$ spec from 100 mA to 120 mA for 83MHz, 90 mA to 100 mA for 66MHz, 60 mA to 63 mA for 40MHz			
*F	2751755	VKN / PYRS	08/14/09	For 12 ns speed, changed I_{CC} spec from 120 mA to 90 mA For 12 ns speed, changed I_{SB1} spec from 50 mA to 10 mA and I_{SB2} spec from 15 mA to 10 mA			
*G	2898399	AJU	03/24/2010	Updated Package Diagrams.			
*H	3109897	AJU	12/14/2010	Added Ordering Code Definitions.			
*	3245199	PRAS	04/30/2011	Dislodged Automotive information to new datasheet (001-68372). Removed the Note "Automotive Product Information is Preliminary." in page 3 Added Acronyms and Units of Measure. Updated in new template.			
*J	3086499	AJU	06/07/2011	Updated Functional Description (Removed "For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines.").			
*K	3540685	TAVA / AJU	03/06/2012	Updated Features (Included Automotive-A Range information). Updated Selection Guide (Included Automotive-A Range information). Updated Operating Range (Included Automotive-A Range information). Updated Electrical Characteristics (Included Automotive-A Range information). Updated Switching Characteristics (Included Automotive-A Range information). Updated Ordering Information (included the part number CY7C1021D-10ZSXA). Updated Package Diagrams.			



Document History Page (continued)

Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
*L 399	3998493	MEMJ	05/13/2013	Replaced all instances of IO with I/O across the document.
				Updated Switching Characteristics: Updated Note 12.
				Updated Switching Waveforms: Updated Figure 6, Figure 7, Figure 8.
				Updated Package Diagrams: spec 51-85082 – Changed revision from *D to *E. spec 51-85087 – Changed revision from *D to *E.
				Completing Sunset Review.
*M	4033925	MEMJ	06/19/2013	Updated Functional Description. Updated Electrical Characteristics.
				Added one more Test Condition " $I_{OH} = -0.1$ mA" for V_{OH} parameter and add maximum value corresponding to that Test Condition. Added Note 3 and referred the same note in maximum value for V_{OH} parameter corresponding to Test Condition " $I_{OH} = -0.1$ mA".



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CY7C1353S-100AXC AS6C8016-55BIN AS7C164A-15PCN 515712X IDT71V67603S133BG IS62WV51216EBLL-45BLI

IS63WV1288DBLL-10HLI IS66WVE2M16ECLL-70BLI 70V639S10BCG IS66WVE4M16EALL-70BLI IS62WV6416DBLL-45BLI

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5962-8855206YA 5962-8866201YA 5962-8866204TA 5962-8866206MA 5962-8866208UA 5962-8872502XA 5962-9062007MXA 5962
9161705MXA 70V3579S6BFI GS882Z18CD-150I M38510/28902BVA 8413202RA 5962-8866203YA 5962-8871203XA 5962
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